

@2

plant

DCR890N65

Phase Control Thyristor Preliminary Information

DS5855-1.0 MAY 2005 (LN23971)

FEATURES

- Double Side Cooling
- High Surge Capability

APPLICATIONS

- Medium Voltage Soft Starts
- High Voltage Power Supplies
- Static Switches

VOLTAGE RATINGS

Part and Ordering Number	Repetitive Peak Voltages V _{DRM} and V _{DRM} V	Conditions
DCR890N65 DCR890N60 DCR890N55 DCR890N50	6500 6000 5500 5000	$\begin{array}{l} T_{vj} = -40^{\circ} \mbox{ C to } 125^{\circ} \mbox{ C}, \\ I_{DRM} = I_{RRM} = 200 \mbox{mA}, \\ V_{DRM}, \mbox{ V}_{RRM} \mbox{ t}_{p} = 10 \mbox{ms}, \\ V_{DSM} \mbox{ \& } V_{RSM} = \\ V_{DRM} \mbox{ \& } V_{RRM} \mbox{ + } 100 \mbox{ vespectively} \end{array}$

Lower voltage grades available.

ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

DCR890N65

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

KEY PARAMETERS

6500V
893A
15000A
1500V/µs
200A/µs

* Higher dV/dt selections available

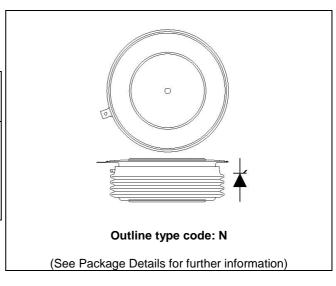


Fig. 1 Package outline



CURRENT RATINGS

 $T_{case} = 60^{\circ}$ C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Double Si	de Cooled			
I _{T(AV)}	Mean on-state current	Half wave resistive load	893	А
I _{T(RMS)}	RMS value	-	1403	А
Ι _Τ	Continuous (direct) on-state current	-	1345	А

SURGE RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
I _{TSM}	Surge (non-repetitive) on-state current	10ms half sine, $T_{case} = 125^{\circ} \text{ C}$	15.0	kA
l ² t	I ² t for fusing	V _R = 0	1.13	MA ² s

THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Condition	Min.	Max.	Units	
R _{th(j-c)}	Thermal resistance – junction to case	Double side cooled	Double side cooled DC		0.0202	° C/W
		Single side cooled	Single side cooled Anode DC		0.0379	° C/W
			Cathode DC	-	0.0451	° C/W
R _{th(c-h)}	Thermal resistance – case to heatsink	Clamping force 23 kN Double side		-	0.004	° C/W
		(with mounting compound)	Single side	-	0.008	° C/W
T_{vj}	Virtual junction temperature	On-state (conducting)		-	135	°C
		Reverse (blocking)		-	125	°C
T _{stg}	Storage temperature range			-55	125	°C
Fm	Clamping force			20.0	25.0	kN



@2 Implant

DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditio	Min.	Max.	Units	
I _{RRM} /I _{DRM}	Peak reverse and off-state current	At V _{RRM} /V _{DRM} , T _{case} = 125° C	At V _{RRM} /V _{DRM} , T _{case} = 125° C			mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V _{DRM} , T _j = 125° C, g	ate open	-	1500	V/µs
dl/dt	Rate of rise of on-state current	From 67% V_{DRM} to 2x $I_{\text{T(AV)}}$	Repetitive 50Hz	-	100	A/µs
		Gate source 30V, 10Ω,	Non-repetitive	-	200	A/µs
		$t_r < 0.5 \mu s, T_j = 125^{\circ} C$				
V _{T(TO)}	Threshold voltage – Low level	100A to 500A at T _{case} = 125°	С	-	0.8919	V
	Threshold voltage – High level	500A to 3000A at T _{case} = 125	-	1.0811	V	
۲ _T	On-state slope resistance – Low level	100A to 500A at $T_{case} = 125^{\circ} C$			1.3041	mΩ
	On-state slope resistance – High level	500A to 3000A at T _{case} = 125° C			0.9595	mΩ
t _{gd}	Delay time	V_D = 67% V_{DRM} , gate source 30V, 10 Ω t_r = 0.5µs, T_j = 25° C		TBD	TBD	μs
	,					
tq	Turn-off time	$T_j = 125^{\circ} C, V_R = 200V, dI/dt$	1000	1600	μs	
		dV _{DR} /dt = 20V/µs linear				
Qs	Stored charge	$I_T = 2000A, T_j = 125^{\circ}C, dI/dt$ $V_{Rpeak} = 60\% V_{drm}, V_R = 40\%$	2400	4370	μC	
ΙL	Latching current	$T_j = 25^{\circ} \text{ C}, V_D = 5 \text{ V}$	TBD	TBD	mA	
Ι _Η	Holding current	$T_j = 25^{\circ} C, R_{G-K} = \infty, I_{TM} = 50^{\circ}$	TBD	TBD	mA	



GATE TRIGGER CHARACTERISTICS AND RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
V _{GT}	Gate trigger voltage	$V_{DRM} = 5V, T_{case} = 25^{\circ} C$	1.5	V
V _{GD}	Gate non-trigger voltage	At V _{DRM} , T _{case} = 125° C	TBD	V
I _{GT}	Gate trigger current	$V_{DRM} = 5V, T_{case} = 25^{\circ} C$	250	mA
I _{GD}	Gate non-trigger current	$V_{DRM} = 5V, T_{case} = 25^{\circ} C$	TBD	mA

CURVES

*YNC> SEMICONDUCTOR

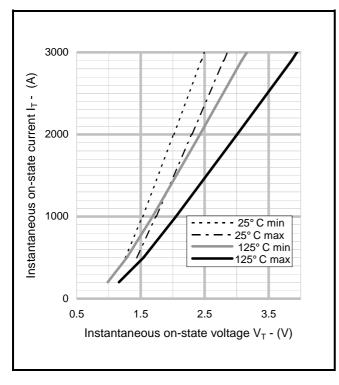


Fig.2 Maximum & minimum on-state characteristics

V_{TM} EQUATION

Where A = -0.434374B = 0.3597001 $V_{TM} = A + Bln (I_T) + C.I_T + D.\sqrt{I_T}$ C = 0.001259D = -0.03983these values are valid for $T_i = 125^{\circ}$ C for $\frac{1}{2}$ 100A to 3000A

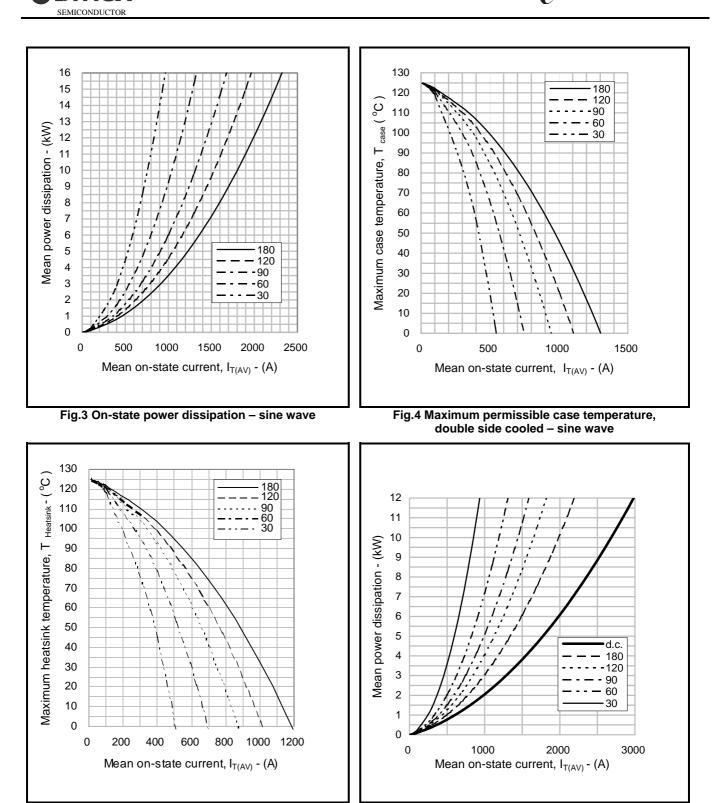
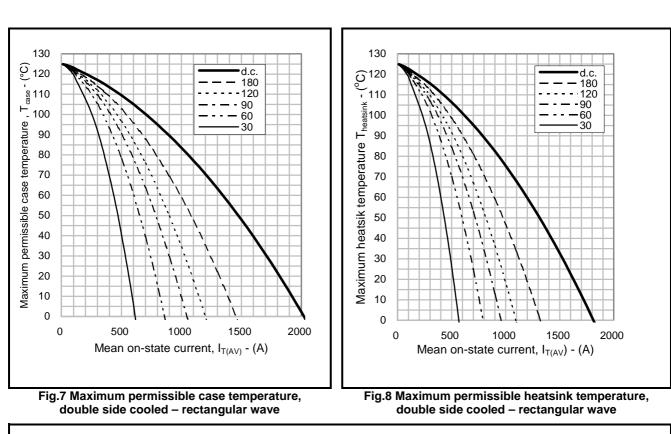


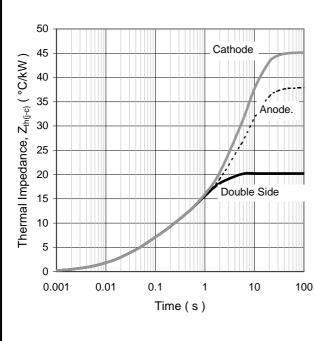
Fig.5 Maximum permissible heatsink temperature, double side cooled – sine wave

Fig.6 On-state power dissipation – rectangular wave

@#YNCX

DCR890N65





SEMICONDUCTOR

		1	2	3	4
Double side cooled	R _i (° C/kW)	1.2849	4.988	5.5614	8.3856
	T _i (s)	0.009195	0.057825	0.43183	1.3814
Anode side cooled	R _i (° C/kW)	1.4937	5.1268	6.8498	24.2935
	T _i (s)	0.010286	0.064874	0.49207	7.2582
Cathode side cooled	R _i (° C/kW)	1.6042	5.285	5.0921	33.032
	T _i (s)	0.010861	0.069332	0.464312	6.671

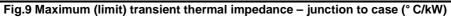
DCR890N65

 $Z_{th} = \Sigma [R_i x (1-exp. (t/T_i))]$ [1]

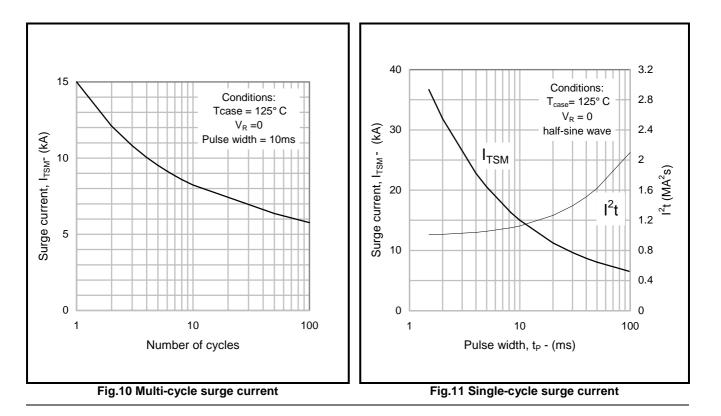
 $\Delta R_{th(j-c)}$ Conduction

Tables show the increments of thermal resistance $R_{\text{th(j-c)}}$ when the device operates at conduction angles other than d.c.

D	Double side cooling			Anode Side Cooling				Cathode Sided Cooling										
	ΔZ_{th}	(z)			$\Delta Z_{th}(z)$		$\Delta Z_{th}(z)$		$\Delta Z_{th}(z)$		$\Delta Z_{th}(z)$		$\Delta Z_{th}(z)$				ΔZ	_{th} (z)
θ°	sine.	rect.		θ°	sine.	rect.		θ°	sine.	rect.								
180	2.25	1.53		180	2.23	1.52		180	2.22	1.52								
120	2.60	2.19		120	2.57	2.16		120	2.56	2.15								
90	2.98	2.55		90	2.94	2.52		90	2.92	2.51								
60	3.32	2.94		60	3.27	2.90		60	3.25	2.88								
30	3.59	3.37		30	3.53	3.32		30	3.50	3.29								
15	3.71	3.60		15	3.65	3.53		15	3.62	3.51								







©2 Implant

DCR890N65



@2 Inplant

PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

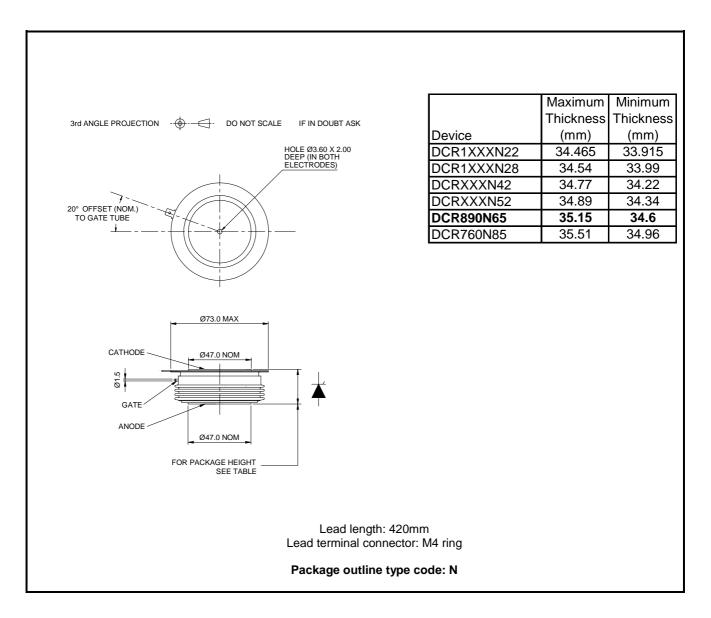


Fig.15 Package outline



POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



HEADQUARTERS OPERATIONS DYNEX SEMICONDUCTOR LTD

Doddington Road, Lincoln Lincolnshire, LN6 3LF. United Kingdom. Tel: +44(0)1522 500500 Fax: +44(0)1522 500550 http://www.dynexsemi.com

e-mail: power_solutions@dynexsemi.com

CUSTOMER SERVICE Tel: +44(0)1522 502753 / 502901. Fax: +44(0)1522 500020

 SALES OFFICES

 Benelux, Italy & Switzerland: Tel: +33(0)1 64 66 42 17. Fax: +33(0)1 64 66 42 19

 France:
 Tel: (01) 60 69 32 36, (02) 47 55 75 53

 Fax: (01) 60 69 31 97, (02) 47 55 75 59

 Germany, Northern Europe, Spain & Rest of World:

 Tel: +44(0)1522 502753 / 502901. Fax: +44(0)1522 500020

 North America:
 Tel: (440) 259 2060. Fax: (440) 259 2059.

 Tel: (949) 733 3005. Fax: (949) 733 2986.

These offices are supported by Representatives and Distributors in many countries world-wide.

© Dynex Semiconductor 2003 TECHNICAL DOCUMENTATION – NOT FOR RESALE. PRODUCED IN UNITED KINGDOM.

This publication is issued to provide information only which (unless agreed by the Company in writing) may not be used, applied or reproduced for any purpose nor form part of any order or contract nor to be regarded as a representation relating to the products or services concerned. No warranty or guarantee express or implied is made regarding the capability, performance or suitability of any product or service. The Company reserves the right to alter without prior notice the specification, design or price of any product or service. Information concerning possible methods of use is provided as a guide only and does not constitute any guarantee that such methods of use will be satisfactory in a specific piece of equipment. It is the user's responsibility to fully determine the performance and suitability of any equipment using such information and to ensure that any publication or data used is up to date and has not been superseded. These products are not suitable for use in any medical products whose failure to perform may result in significant injury or death to the user. All products and materials are sold and services provided subject to the Company's conditions of sale, which are available on request.

All brand names and product names used in this publication are trademarks, registered trademarks or trade names of their respective owners.